

## ABSTRACT OF THE DISCLOSURE

A method for testing an output circuit of a semiconductor device including a plurality of output circuits includes the step of turning ON p-ch and n-ch MIS transistors of a subject output circuit, turning ON and OFF one and the other, respectively, of p-ch and n-ch MIS transistors of another output circuit used as a reference output circuit, measuring the potential difference between the output terminal of the subject output circuit and the output terminal of the reference output circuit and the penetrating current of the subject output circuit, and calculating the ON-resistance of the p-ch or n-ch transistor of the subject output circuit.